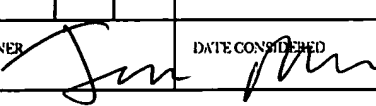
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Vladimir Segal et al.		FILING DATE December 16, 1999	
				GROUP 1742			
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
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	AE						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AF						
	AG						
	AH						
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
jm	AK		S. Ferrasse et al., "ECAE Targets with Sub-Micron Grain Structures Improve Sputtering Performance and Cost-of-Ownership", Semiconductor Manufacturing, Vol. 4, Issue 10, October 2003, pp. 76-92.				
jm	AL		R.Z. Valiev et al., "Bulk Nanostructured materials from severe plastic deformation", Progress in Materials Science, Vol. 45, 2000, pp. 103-189.				
jm	AM		R.Z. Valiev et al., "Plastic deformation of alloys with submicron-grained structure", Materials Science and Engineering, A137 (1991) pp. 35-40.				
jm	AN		Ferrasse et al., "Microstructure and Properties of Copper and Aluminum Alloy 3003 Heavily Worked by Equal Channel Angular Extrusion", Metallurgical and Materials Transactions, Vol. 28A, April 1997, pp. 1047-1057.				
	AR						
	AS						
	AT						
EXAMINER			DATE CONSIDERED 11/17/05				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
30-5022(4013)SERIAL NO.
09/783,377LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Vladimir Segal et al.FILING DATE
February 13, 2001GROUP
1742

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
Jan	AA	5,850,755	12-1998	Segal et al.			
	AB						
	AC						
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AF							
	AG							
	AH							
	AI							
	AJ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

Jan	AK		F. J. Humphreys et al., "Developing stable fine-grain microstructures by large strain deformation", Phil. Trans. R. Soc. Lond. A, June 15, 1999, Vol. 357 #1756, pp. 1663-1681.
Jan	AL		S. Ferrasse et al., "Texture evolution during equal channel angular extrusion Part I. Effect of route, number of passes and initial texture", Materials Science and Engineering, Vol. 368, March 15, 2004, pp. 28-40.
Jan	AM		V.M. Segal, "Equal channel angular extrusion: from macromechanics to structure formation", Materials Science & Engineering A271, November 1, 1999, pp. 322-333.
Jan	AN		Rustan Z. Valiev et al., "SPD-Processed Ultra-Fine Grained Ti Materials for Medical Applications", Advanced Materials & Processes, December 2003, pp. 33-34.
Jan	AR		Segal et al., "Plastic Working of Metals by Simple Shear", Russian Metall. Vol. 1, pp. 99-105, 1991.
Jan	AS		M. Furukawa et al., "Microhardness Measurements and the Hall-Petch Relationship in an Al-Mg Alloy with Submicrometer Grain Size", Acta Mater. Vol. 44, No. 11, pp. 4619-4629, 1996.
Jan	AT		Yoshinori Iwahashi et al., "Microstructural Characteristics of Ultrafine-Grained Aluminum Produced Using Equal-Channel Angular Pressing", Metallurgical and Materials Transactions, Vol. 29A, pp. 2245-2252, September 1998.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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